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LIST OF REFERENCES CITED BY APPLICANT Tatsuya OSHITA, et al.								
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				June 1, 2006		1794		
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
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Examiner	/Erik Kashnikow/				Date Considered 01/09/2009			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in								
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